

Notice of References Cited	Application/Control No. 09/998,195		Applicant(s)/Patent Under Reexamination SENANAYAKE ET AL.	
	Examiner SHAIENDRA - KUMAR		Art Unit 1621	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,331,571 B1	12-2001	Jerussi et al.	514/646
	B	US-			
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	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Fang et al, Tetrahedron Assymetry, vol 10, pages 4477-4480, 1999.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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